

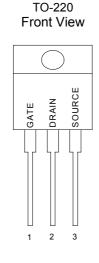
## **GENERAL DESCRIPTION**

This Power MOSFET is designed for low voltage, high speed power switching applications such as switching regulators, converters, solenoid and relay drivers.

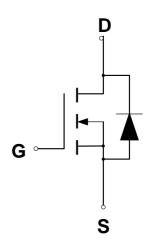
## **FEATURES**

- Silicon Gate for Fast Switching Speeds
- ◆ Low R<sub>DS(on)</sub> to Minimize On-Losses. Specified at Elevated Temperature
- ◆ Rugged SOA is Power Dissipation Limited
- Source-to-Drain Characterized for Use With Inductive Loads

# **PIN CONFIGURATION**



# **SYMBOL**



N-Channel MOSFET

### ORDERING INFORMATION

Part Number	Package
CMT18N20N220	TO-220

# **ABSOLUTE MAXIMUM RATINGS**

Rating	Symbol	Value	Unit
Drain to Current — Continuous		18	Α
- Pulsed	$I_{DM}$	72	
Gate-to-Source Voltage — Continue		±20	V
<ul><li>Non-repetitive</li></ul>	$V_{GSM}$	±40	V
Total Power Dissipation		125	W
Derate above 25°ℂ		1.00	W/°C
Operating and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	$^{\circ}\!\mathbb{C}$
Single Pulse Drain-to-Source Avalanche Energy $-T_J = 25^{\circ}$ C		224	mJ
$(V_{DD} = 100V, V_{GS} = 10V, I_{L} = 18A, L = 1.38mH, R_{G} = 25\Omega)$			
Thermal Resistance — Junction to Case	$\theta_{JC}$	1.00	°C/W
<ul> <li>Junction to Ambient</li> </ul>	$\theta_{JA}$	62.5	
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 10 seconds	$T_L$	260	$^{\circ}\mathbb{C}$

(1) Pulse Width and frequency is limited by TJ(max) and thermal response



# **ELECTRICAL CHARACTERISTICS**

Unless otherwise specified,  $T_J = 25^{\circ}C$ .

			CMT18N20			
Characteristic		Symbol	Min	Тур	Max	Units
Drain-Source Breakdown Voltage		V <sub>(BR)DSS</sub>	200			V
$(V_{GS} = 0 \text{ V}, I_D = 250 \ \mu \text{ A})$						
Drain-Source Leakage Current		I <sub>DSS</sub>				mA
$(V_{DS} = Rated V_{DSS}, V_{GS} = 0 V)$					0.025	
$(V_{DS} = 0.8 \text{Rated } V_{DSS}, V_{GS} = 0 \text{ V}, T_{J} = 125^{\circ}\text{C})$					1.0	
Gate-Source Leakage Current-Forward		$I_{GSSF}$			100	nA
$(V_{gsf} = 20 \text{ V}, V_{DS} = 0 \text{ V})$						
Gate-Source Leakage Current-Rev	erse	I <sub>GSSR</sub>			100	nA
$(V_{gsr} = 20 \text{ V}, V_{DS} = 0 \text{ V})$						
Gate Threshold Voltage		$V_{GS(th)}$	2.0		4.0	V
$(V_{DS} = V_{GS}, I_{D} = 250 \mu A)$						
Static Drain-Source On-Resistance	$(V_{GS} = 10 \text{ V}, I_D = 10 \text{A}) *$	R <sub>DS(on)</sub>			0.18	Ω
Drain-Source On-Voltage ( $V_{GS}$ = 10	(V)	$V_{DS(on)}$			6.0	V
$(I_D = 5.0 \text{ A})$						
Forward Transconductance (V <sub>DS</sub> =	50 V, I <sub>D</sub> = 10 A) *	<b>g</b> FS	6.8			mhos
Input Capacitance	$(V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$	C <sub>iss</sub>			1600	pF
Output Capacitance	f = 1.0 MHz)	Coss			750	pF
Reverse Transfer Capacitance	I = 1.0 MHZ)	C <sub>rss</sub>			300	pF
Turn-On Delay Time	(V <sub>DD</sub> = 30 V, I <sub>D</sub> = 10 A.	$t_{\sf d(on)}$			30	ns
Rise Time	$V_{DD} = 30 \text{ V}, I_D = 10 \text{ A},$ $V_{GS} = 10 \text{ V},$ $R_G = 4.7\Omega)^*$	t <sub>r</sub>			60	ns
Turn-Off Delay Time		$t_{d(off)}$			80	ns
Fall Time	NG - 4.752)	t <sub>f</sub>			60	ns
Total Gate Charge	$(V_{DS} = 0.8Rated V_{DSS}, I_D = Rated I_D,$	$Q_g$		36	63	nC
Gate-Source Charge	$V_{DS} = 0.0$ Kateu $V_{DSS}$ , $I_D = Kateu I_D$ , $V_{GS} = 10 \text{ V}$ )*	$Q_gs$		16		nC
Gate-Drain Charge	V <sub>GS</sub> - 10 V)	$Q_{gd}$		26		nC
Internal Drain Inductance		L <sub>D</sub>		4.5		nH
(Measured from the drain lead 0.	25" from package to center of die)					
Internal Drain Inductance		Ls		7.5		nH
(Measured from the source lead	0.25" from package to source bond pad)					
SOURCE-DRAIN DIODE CHARAC	CTERISTICS					
Forward On-Voltage(1)	(I <sub>S</sub> = Rated I <sub>D</sub> ,	$V_{SD}$			1.5	V
Forward Turn-On Time		t <sub>on</sub>		**		ns
Reverse Recovery Time	$d_{ls}/d_t = 100A/\mu s)$	t <sub>rr</sub>		450		ns

<sup>\*</sup> Pulse Test: Pulse Width  $\,\leq\!300\mu\text{s},\,\text{Duty Cycle}\,\,\leq\!2\%$ 

<sup>\*\*</sup> Negligible, Dominated by circuit inductance



# TYPICAL ELECTRICAL CHARACTERISTICS

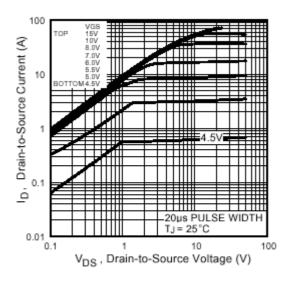


Fig 1. Typical Output Characteristics

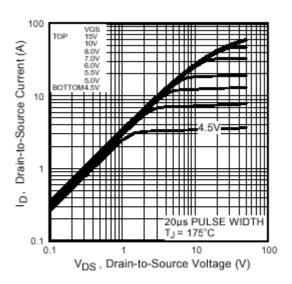


Fig 2. Typical Output Characteristics

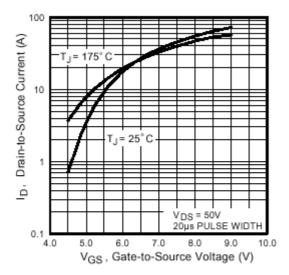


Fig 3. Typical Transfer Characteristics

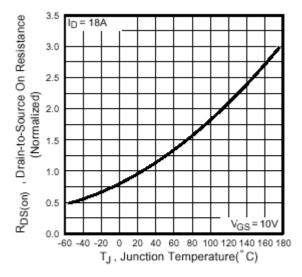


Fig 4. Normalized On-Resistance Vs. Temperature



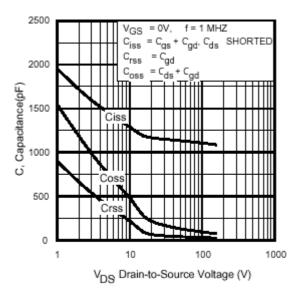


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

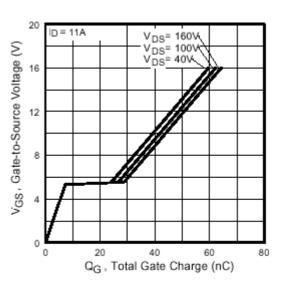


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

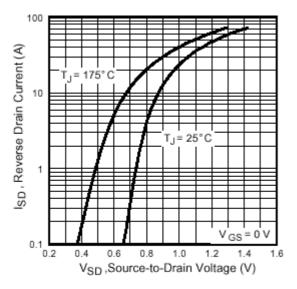


Fig 7. Typical Source-Drain Diode Forward Voltage

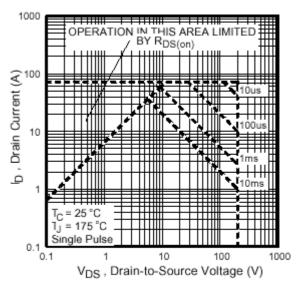


Fig 8. Maximum Safe Operating Area



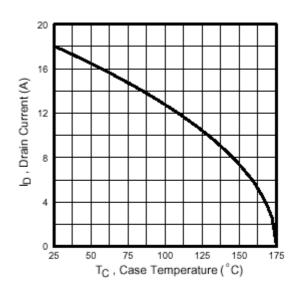


Fig 9. Maximum Drain Current Vs. Case Temperature

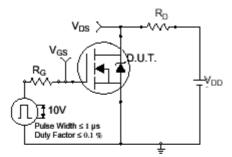


Fig 10a. Switching Time Test Circuit

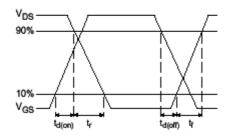


Fig 10b. Switching Time Waveforms

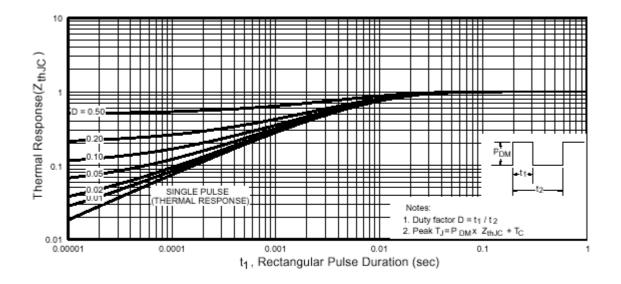


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

0.184

0.111

0.036

0.054

0.021

0.054

0.406

0.350

0.491

0.204

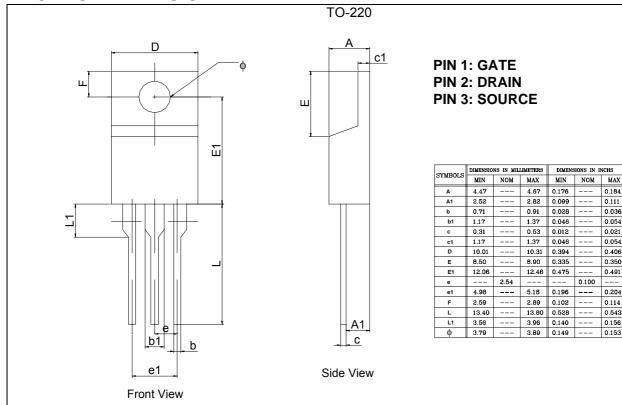
0.114

0.156

0.153



# **PACKAGE DIMENSION**





### **IMPORTANT NOTICE**

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